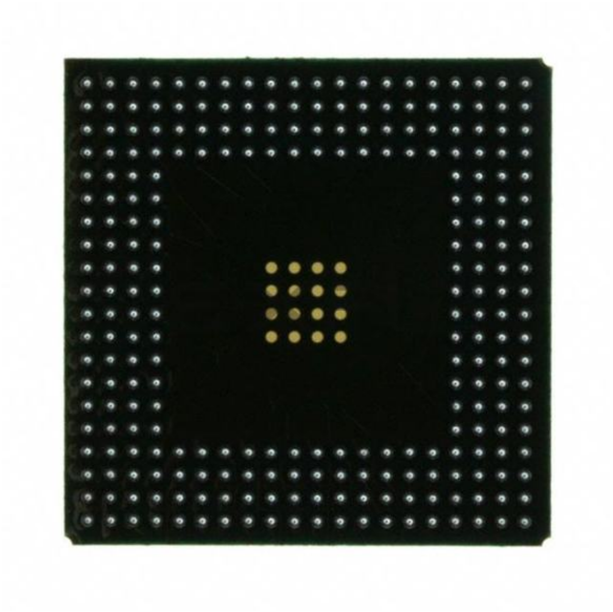
AMD Xilinx - XCV50-5BG256C Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	384
Number of Logic Elements/Cells	1728
Total RAM Bits	32768
Number of I/O	180
Number of Gates	57906
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-BBGA
Supplier Device Package	256-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv50-5bg256c

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99-02/99	1.2-1.3	Both versions updated package drawings and specs.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, “0” hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T_{IJITCC} parameter, changed T_{OJIT} to T_{OPHASE}.
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V_{CCO} in CS144 package on p.43.
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified “Pins not listed...” statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	• Added XCV400 values to table under **Minimum Clock-to-Out for Virtex Devices**. • Corrected Units column in table under **IOB Input Switching Characteristics**. • Added values to table under **CLB SelectRAM Switching Characteristics**.
10/00	2.4	• Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. • Corrected **BG256 Pin Function Diagram**.
04/01	2.5	• Revised minimums for **Global Clock Set-Up and Hold for LVTTL Standard, with DLL**. • Converted file to modularized format. See Virtex Data Sheet section.
03/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)
- DS003-3, Virtex 2.5V FPGAs: DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)

Virtex™ 2.5 V Field Programmable Gate Arrays

DS003-2 (v4.0) March 1, 2013

Product Specification

Architectural Description

Virtex Array

The Virtex user-programmable gate array, shown in Figure 1, comprises two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing logic
- IOBs provide the interface between the package pins and the CLBs

CLBs interconnect through a general routing matrix (GRM). The GRM comprises an array of routing switches located at the intersections of horizontal and vertical routing channels. Each CLB nests into a VersaBlock™ that also provides local routing resources to connect the CLB to the GRM.

The VersaRing™ I/O interface provides additional routing resources around the periphery of the device. This routing improves I/O routability and facilitates pin locking.

The Virtex architecture also includes the following circuits that connect to the GRM.

- Dedicated block memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- 3-State buffers (BUFTs) associated with each CLB that drive dedicated segmentable horizontal routing resources

Values stored in static memory cells control the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Input/Output Block

The Virtex IOB, Figure 2, features SelectIO™ inputs and outputs that support a wide variety of I/O signalling standards, see Table 1.

The three IOB storage elements function either as edge-triggered D-type flip-flops or as level sensitive latches. Each IOB has a clock signal (CLK) shared by the three flip-flops and independent clock enable signals for each flip-flop.

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

The output buffer and all of the IOB control signals have independent polarity controls.

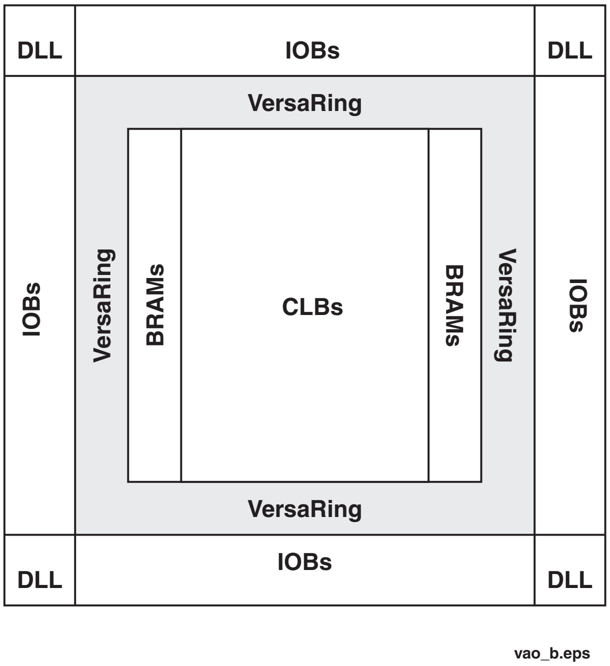

Figure 1: **Virtex Architecture Overview**

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. Two forms of over-voltage protection are provided, one that permits 5 V compliance, and one that does not. For 5 V compliance, a Zener-like structure connected to ground turns on when the output rises to approximately 6.5 V. When PCI 3.3 V compliance is required, a conventional clamp diode is connected to the output supply voltage, V_{CCO}.

Optional pull-up and pull-down resistors and an optional weak-keeper circuit are attached to each pad. Prior to configuration, all pins not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but inputs can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins will float. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex IOBs support IEEE 1149.1-compatible boundary scan testing.

more I/O pins convert to V_{REF} pins. Since these are always a superset of the V_{REF} pins used for smaller devices, it is possible to design a PCB that permits migration to a larger device if necessary. All the V_{REF} pins for the largest device anticipated must be connected to the V_{REF} voltage, and not used for I/O.

In smaller devices, some V_{CCO} pins used in larger devices do not connect within the package. These unconnected pins can be left unconnected externally, or can be connected to the V_{CCO} voltage to permit migration to a larger device if necessary.

In TQ144 and PQ/HQ240 packages, all V_{CCO} pins are bonded together internally, and consequently the same V_{CCO} voltage must be connected to all of them. In the CS144 package, bank pairs that share a side are interconnected internally, permitting four choices for V_{CCO}. In both cases, the V_{REF} pins remain internally connected as eight banks, and can be used as described previously.

Configurable Logic Block

The basic building block of the Virtex CLB is the logic cell (LC). An LC includes a 4-input function generator, carry logic, and a storage element. The output from the function generator in each LC drives both the CLB output and the D input of the flip-flop. Each Virtex CLB contains four LCs, organized in two similar slices, as shown in Figure 4.

Figure 5 shows a more detailed view of a single slice.

In addition to the four basic LCs, the Virtex CLB contains logic that combines function generators to provide functions of five or six inputs. Consequently, when estimating the number of system gates provided by a given device, each CLB counts as 4.5 LCs.

Look-Up Tables

Virtex function generators are implemented as 4-input look-up tables (LUTs). In addition to operating as a function generator, each LUT can provide a 16 x 1-bit synchronous RAM. Furthermore, the two LUTs within a slice can be combined to create a 16 x 2-bit or 32 x 1-bit synchronous RAM, or a 16x1-bit dual-port synchronous RAM.

The Virtex LUT can also provide a 16-bit shift register that is ideal for capturing high-speed or burst-mode data. This mode can also be used to store data in applications such as Digital Signal Processing.

Storage Elements

The storage elements in the Virtex slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by the function generators within the slice or directly from slice inputs, bypassing the function generators.

In addition to Clock and Clock Enable signals, each Slice has synchronous set and reset signals (SR and BY). SR forces a storage element into the initialization state specified for it in the configuration. BY forces it into the opposite state. Alternatively, these signals can be configured to operate asynchronously. All of the control signals are independently invertible, and are shared by the two flip-flops within the slice.

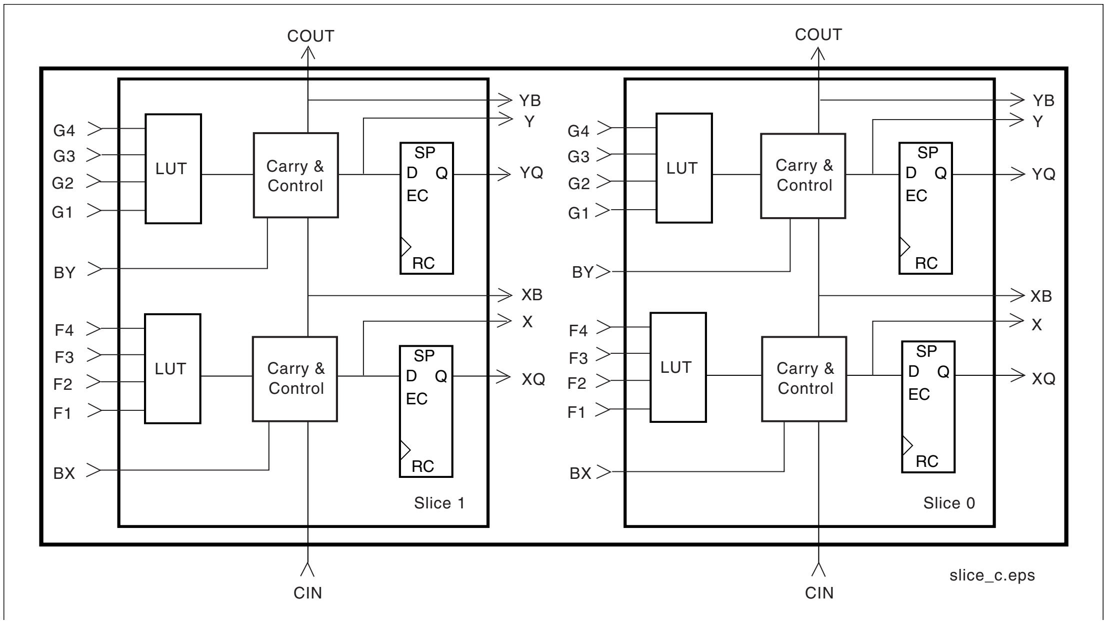

Figure 4: **2-Slice Virtex CLB**

Each block SelectRAM cell, as illustrated in Figure 6, is a fully synchronous dual-ported 4096-bit RAM with independent control signals for each port. The data widths of the two ports can be configured independently, providing built-in bus-width conversion.

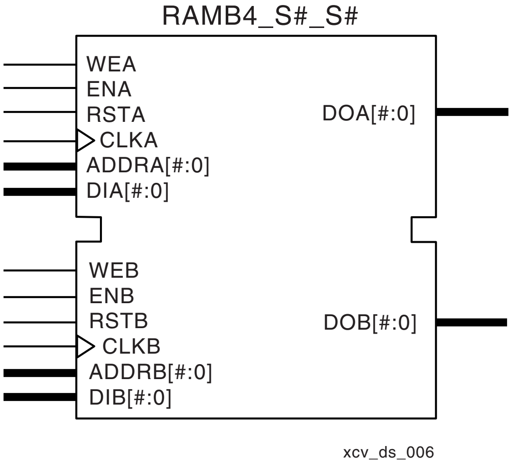

Figure 6: **Dual-Port Block SelectRAM**

Table 4 shows the depth and width aspect ratios for the block SelectRAM.

Table 4: **Block SelectRAM Port Aspect Ratios**

Width	Depth	ADDR Bus	Data Bus
1	4096	ADDR<11:0>	DATA<0>
2	2048	ADDR<10:0>	DATA<1:0>
4	1024	ADDR<9:0>	DATA<3:0>
8	512	ADDR<8:0>	DATA<7:0>
16	256	ADDR<7:0>	DATA<15:0>

The Virtex block SelectRAM also includes dedicated routing to provide an efficient interface with both CLBs and other block SelectRAMs. Refer to XAPP130 for block SelectRAM timing waveforms.

Programmable Routing Matrix

It is the longest delay path that limits the speed of any worst-case design. Consequently, the Virtex routing architecture and its place-and-route software were defined in a single optimization process. This joint optimization minimizes long-path delays, and consequently, yields the best system performance.

The joint optimization also reduces design compilation times because the architecture is software-friendly. Design cycles are correspondingly reduced due to shorter design iteration times.

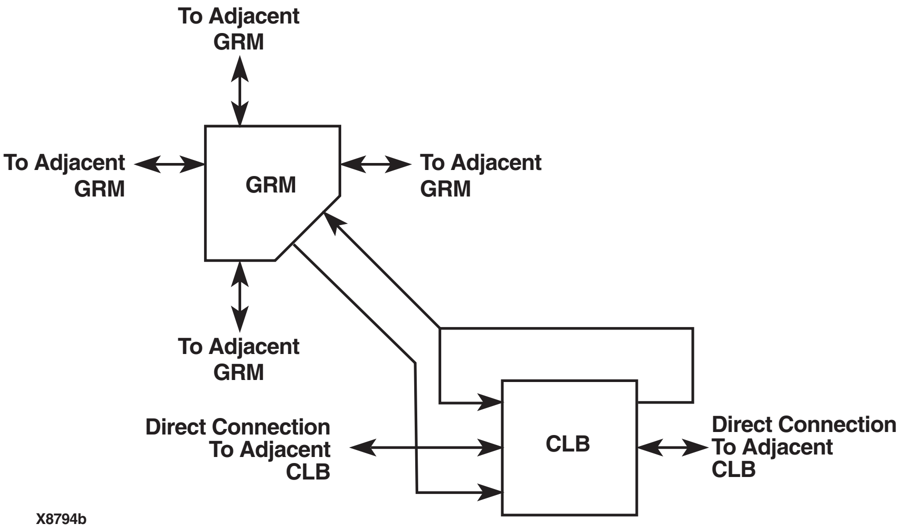

Figure 7: **Virtex Local Routing**

Local Routing

The VersaBlock provides local routing resources, as shown in Figure 7, providing the following three types of connections.

- Interconnections among the LUTs, flip-flops, and GRM
- Internal CLB feedback paths that provide high-speed connections to LUTs within the same CLB, chaining them together with minimal routing delay
- Direct paths that provide high-speed connections between horizontally adjacent CLBs, eliminating the delay of the GRM.

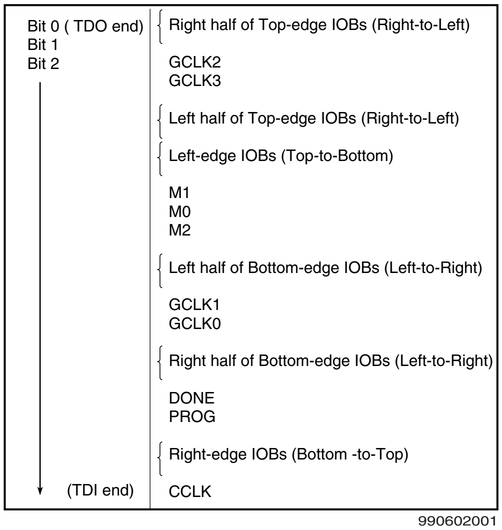

Figure 11: **Boundary Scan Bit Sequence**

Table 5: **Boundary Scan Instructions**

Boundary-Scan Command	Binary Code(4:0)	Description
EXTEST	00000	Enables boundary-scan EXTEST operation
SAMPLE/PRELOAD	00001	Enables boundary-scan SAMPLE/PRELOAD operation
USER 1	00010	Access user-defined register 1
USER 2	00011	Access user-defined register 2
CFG_OUT	00100	Access the configuration bus for read operations.
CFG_IN	00101	Access the configuration bus for write operations.
INTEST	00111	Enables boundary-scan INTEST operation
USERCODE	01000	Enables shifting out USER code
IDCODE	01001	Enables shifting out of ID Code
HIGHZ	01010	3-states output pins while enabling the Bypass Register
JSTART	01100	Clock the start-up sequence when StartupClk is TCK
BYPASS	11111	Enables BYPASS
RESERVED	All other codes	Xilinx reserved instructions

Identification Registers

The IDCODE register is supported. By using the IDCODE, the device connected to the JTAG port can be determined.

The IDCODE register has the following binary format:

vvvv:ffff:fffa:aaaa:aaaa:cccc:cccc:ccc1

where

v = the die version number

f = the family code (03h for Virtex family)

a = the number of CLB rows (ranges from 010h for XCV50 to 040h for XCV1000)

c = the company code (49h for Xilinx)

The USERCODE register is supported. By using the USERCODE, a user-programmable identification code can be loaded and shifted out for examination. The identification code is embedded in the bitstream during bitstream generation and is valid only after configuration.

Table 6: **IDCODEs Assigned to Virtex FPGAs**

FPGA	IDCODE
XCV50	v0610093h
XCV100	v0614093h
XCV150	v0618093h
XCV200	v061C093h
XCV300	v0620093h
XCV400	v0628093h
XCV600	v0630093h
XCV800	v0638093h
XCV1000	v0640093h

Including Boundary Scan in a Design

Since the boundary scan pins are dedicated, no special element needs to be added to the design unless an internal data register (USER1 or USER2) is desired.

If an internal data register is used, insert the boundary scan symbol and connect the necessary pins as appropriate.

Development System

Virtex FPGAs are supported by the Xilinx Foundation and Alliance CAE tools. The basic methodology for Virtex design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation (for example, Synopsys FPGA Express), while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under the Xilinx Design Manager (XDM™) software, providing design-

Configuration

Virtex devices are configured by loading configuration data into the internal configuration memory. Some of the pins used for this are dedicated configuration pins, while others can be re-used as general purpose inputs and outputs once configuration is complete.

The following are dedicated pins:

- Mode pins (M2, M1, M0)
- Configuration clock pin (CCLK)
- $\overline{\text{PROGRAM}}$ pin
- DONE pin
- Boundary-scan pins (TDI, TDO, TMS, TCK)

Depending on the configuration mode chosen, CCLK can be an output generated by the FPGA, or it can be generated externally and provided to the FPGA as an input. The $\overline{\text{PROGRAM}}$ pin must be pulled High prior to reconfiguration.

Note that some configuration pins can act as outputs. For correct operation, these pins can require a V_{CCO} of 3.3 V to permit LVTTL operation. All the pins affected are in banks 2 or 3. The configuration pins needed for SelectMap (CS, Write) are located in bank 1.

After Virtex devices are configured, unused IOBs function as 3-state OBUFTs with weak pull downs. For a more detailed description than that given below, see the XAPP138, Virtex Configuration and Readback.

Configuration Modes

Virtex supports the following four configuration modes.

- Slave-serial mode
- Master-serial mode
- SelectMAP mode
- Boundary-scan mode

The Configuration mode pins (M2, M1, M0) select among these configuration modes with the option in each case of having the IOB pins either pulled up or left floating prior to configuration. The selection codes are listed in Table 7.

Configuration through the boundary-scan port is always available, independent of the mode selection. Selecting the boundary-scan mode simply turns off the other modes. The three mode pins have internal pull-up resistors, and default to a logic High if left unconnected. However, it is recommended to drive the configuration mode pins externally.

Table 7: **Configuration Codes**

Configuration Mode	M2	M1	M0	CCLK Direction	Data Width	Serial D_{out}	Configuration Pull-ups
Master-serial mode	0	0	0	Out	1	Yes	No
Boundary-scan mode	1	0	1	N/A	1	No	No
SelectMAP mode	1	1	0	In	8	No	No
Slave-serial mode	1	1	1	In	1	Yes	No
Master-serial mode	1	0	0	Out	1	Yes	Yes
Boundary-scan mode	0	0	1	N/A	1	No	Yes
SelectMAP mode	0	1	0	In	8	No	Yes
Slave-serial mode	0	1	1	In	1	Yes	Yes

Slave-Serial Mode

In slave-serial mode, the FPGA receives configuration data in bit-serial form from a serial PROM or other source of serial configuration data. The serial bitstream must be setup at the DIN input pin a short time before each rising edge of an externally generated CCLK.

For more information on serial PROMs, see the PROM data sheet at:
http://www.xilinx.com/bvdocs/publications/ds026.pdf.

Multiple FPGAs can be daisy-chained for configuration from a single source. After a particular FPGA has been configured, the data for the next device is routed to the DOUT pin. The data on the DOUT pin changes on the rising edge of CCLK.

The change of DOUT on the rising edge of CCLK differs from previous families, but does not cause a problem for mixed configuration chains. This change was made to improve serial configuration rates for Virtex-only chains.

Figure 12 shows a full master/slave system. A Virtex device in slave-serial mode should be connected as shown in the third device from the left.

Slave-serial mode is selected by applying <111> or <011> to the mode pins (M2, M1, M0). A weak pull-up on the mode pins makes slave-serial the default mode if the pins are left unconnected. However, it is recommended to drive the configuration mode pins externally. Figure 13 shows slave-serial mode programming switching characteristics.

Table 8 provides more detail about the characteristics shown in Figure 13. Configuration must be delayed until the $\overline{\text{INIT}}$ pins of all daisy-chained FPGAs are High.

Master-Serial Mode

In master-serial mode, the CCLK output of the FPGA drives a Xilinx Serial PROM that feeds bit-serial data to the DIN input. The FPGA accepts this data on each rising CCLK edge. After the FPGA has been loaded, the data for the next device in a daisy-chain is presented on the DOUT pin after the rising CCLK edge.

The interface is identical to slave-serial except that an internal oscillator is used to generate the configuration clock (CCLK). A wide range of frequencies can be selected for CCLK which always starts at a slow default frequency. Configuration bits then switch CCLK to a higher frequency for the remainder of the configuration. Switching to a lower frequency is prohibited.

The CCLK frequency is set using the ConfigRate option in the bitstream generation software. The maximum CCLK frequency that can be selected is 60 MHz. When selecting a CCLK frequency, ensure that the serial PROM and any daisy-chained FPGAs are fast enough to support the clock rate.

On power-up, the CCLK frequency is 2.5 MHz. This frequency is used until the ConfigRate bits have been loaded when the frequency changes to the selected ConfigRate. Unless a different frequency is specified in the design, the default ConfigRate is 4 MHz.

Figure 12 shows a full master/slave system. In this system, the left-most device operates in master-serial mode. The remaining devices operate in slave-serial mode. The SPROM $\overline{\text{RESET}}$ pin is driven by $\overline{\text{INIT}}$, and the $\overline{\text{CE}}$ input is driven by DONE. There is the potential for contention on the DONE pin, depending on the start-up sequence options chosen.

Figure 14 shows the timing of master-serial configuration. Master-serial mode is selected by a <000> or <100> on the mode pins (M2, M1, M0). Table 8 shows the timing information for Figure 14.

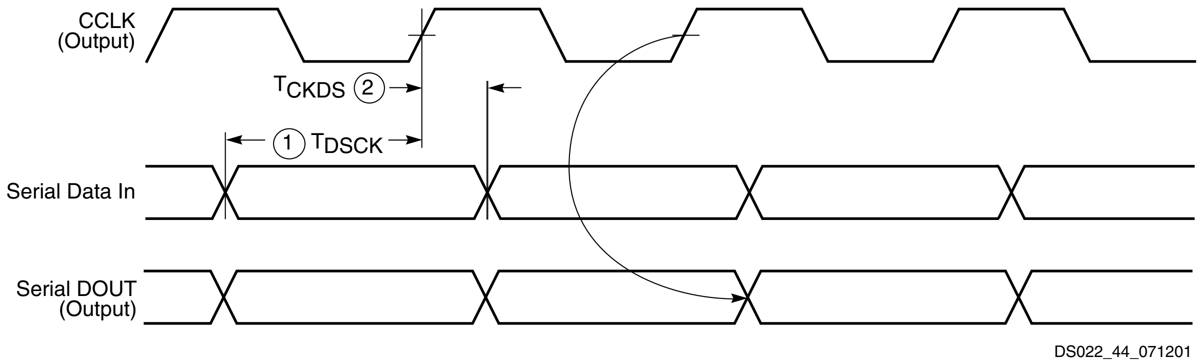

Figure 14: **Master-Serial Mode Programming Switching Characteristics**

At power-up, V_{CC} must rise from 1.0 V to V_{CC} min in less than 50 ms, otherwise delay configuration by pulling $\overline{\text{PROGRAM}}$ Low until V_{CC} is valid.

The sequence of operations necessary to configure a Virtex FPGA serially appears in Figure 15.

SelectMAP Mode

The SelectMAP mode is the fastest configuration option. Byte-wide data is written into the FPGA with a BUSY flag controlling the flow of data.

An external data source provides a byte stream, CCLK, a Chip Select ($\overline{\text{CS}}$) signal and a Write signal ($\overline{\text{WRITE}}$). If BUSY is asserted (High) by the FPGA, the data must be held until BUSY goes Low.

Data can also be read using the SelectMAP mode. If $\overline{\text{WRITE}}$ is not asserted, configuration data is read out of the FPGA as part of a readback operation.

In the SelectMAP mode, multiple Virtex devices can be chained in parallel. DATA pins (D7:D0), CCLK, $\overline{\text{WRITE}}$, $\overline{\text{BUSY}}$, $\overline{\text{PROGRAM}}$, DONE, and $\overline{\text{INIT}}$ can be connected in parallel between all the FPGAs. Note that the data is organized with the MSB of each byte on pin DO and the LSB of each byte on D7. The $\overline{\text{CS}}$ pins are kept separate, insuring that each FPGA can be selected individually. $\overline{\text{WRITE}}$ should be Low before loading the first bitstream and returned High after the last device has been programmed. Use $\overline{\text{CS}}$ to select the appropriate FPGA for loading the bitstream and sending the configuration data. at the end of the bitstream, deselect the loaded device and select the next target FPGA by setting its $\overline{\text{CS}}$ pin High. A free-running oscillator or other externally generated signal can be used for CCLK. The $\overline{\text{BUSY}}$ signal can be ignored for frequencies below 50 MHz. For details about frequencies above 50 MHz, see XAPP138, Virtex Configuration and Readback. Once all the devices have been programmed, the DONE pin goes High.

3. At the rising edge of CCLK: If BUSY is Low, the data is accepted on this clock. If BUSY is High (from a previous write), the data is not accepted. Acceptance will instead occur on the first clock after BUSY goes Low, and the data must be held until this has happened.
4. Repeat steps 2 and 3 until all the data has been sent.
5. De-assert $\overline{CS}$ and $\overline{WRITE}$.

A flowchart for the write operation appears in Figure 17. Note that if CCLK is slower than f_{CCNH}, the FPGA never asserts BUSY. In this case, the above handshake is unnecessary, and data can simply be entered into the FPGA every CCLK cycle.

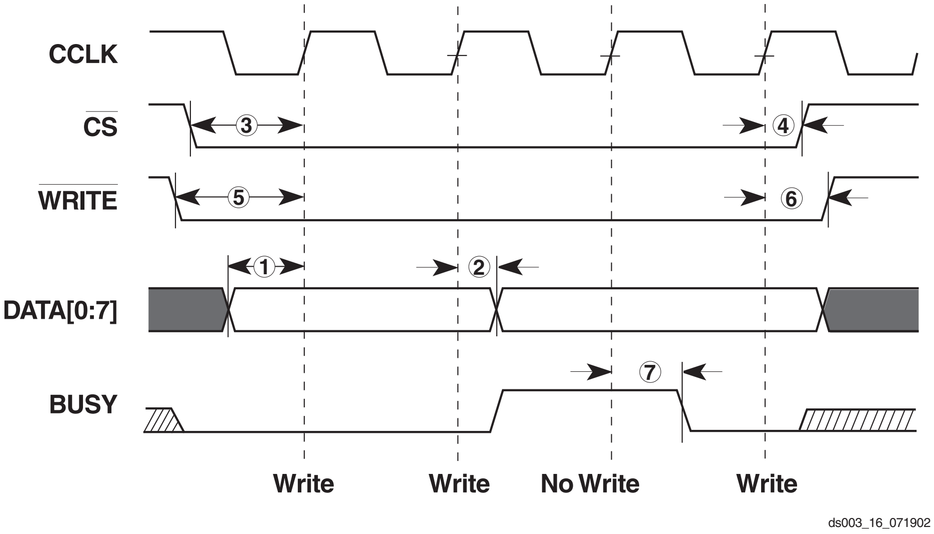

Figure 16: **Write Operations**

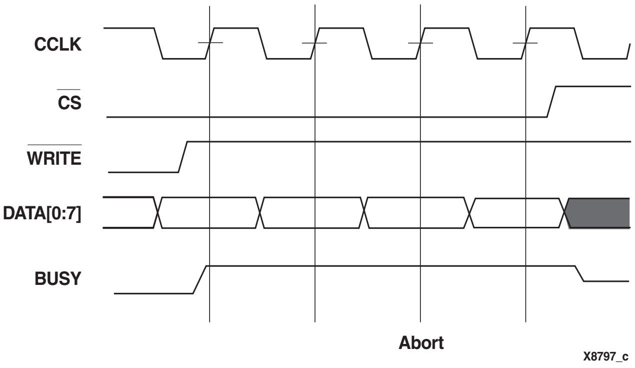

Figure 18: **SelectMAP Write Abort Waveforms**

Boundary-Scan Mode

In the boundary-scan mode, configuration is done through the IEEE 1149.1 Test Access Port. Note that the PROGRAM pin must be pulled High prior to reconfiguration. A Low on the PROGRAM pin resets the TAP controller and no JTAG operations can be performed.

Configuration through the TAP uses the CFG_IN instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

1. Load the CFG_IN instruction into the boundary-scan instruction register (IR)
2. Enter the Shift-DR (SDR) state
3. Shift a configuration bitstream into TDI
4. Return to Run-Test-Idle (RTI)
5. Load the JSTART instruction into IR
6. Enter the SDR state
7. Clock TCK through the startup sequence
8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or 001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

Configuration Sequence

The configuration of Virtex devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting PROGRAM. The end of the memory-clearing phase is signalled by INIT going High, and the completion of the entire process is signalled by DONE going High.

The power-up timing of configuration signals is shown in Figure 19. The corresponding timing characteristics are listed in Table 10.

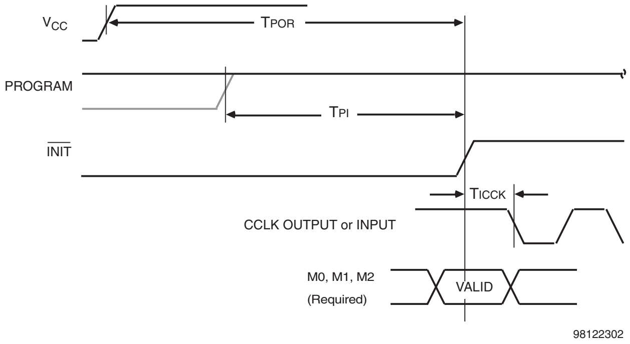

Figure 19: **Power-Up Timing Configuration Signals**

Table 10: **Power-up Timing Characteristics**

Description	Symbol	Value	Units
Power-on Reset	T_{POR}	2.0	ms, max
Program Latency	T_{PL}	100.0	µs, max
CCLK (output) Delay	T_{ICCK}	0.5	µs, min
		4.0	µs, max
Program Pulse Width	$T_{PROGRAM}$	300	ns, min

Delaying Configuration

INIT can be held Low using an open-drain driver. An open-drain is required since INIT is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after DONE goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the DONE pins of multiple devices all going High, forcing the devices to start in synchronism. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.

Data Stream Format

Virtex devices are configured by sequentially loading frames of data. Table 11 lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 "Virtex Configuration Architecture Advanced Users Guide".

Table 11: **Virtex Bit-Stream Lengths**

Device	# of Configuration Bits
XCV50	559,200
XCV100	781,216
XCV150	1,040,096
XCV200	1,335,840
XCV300	1,751,808
XCV400	2,546,048
XCV600	3,607,968
XCV800	4,715,616
XCV1000	6,127,744

Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138**:** *Virtex FPGA Series Configuration and Readback*, available online at www.xilinx.com.

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T_{IJITCC} parameter, changed T_{OJIT} to T_{OPHASE}.
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V_{CCO} in CS144 package on p.43.

Virtex DC Characteristics

Absolute Maximum Ratings

Symbol	Description(1)			Units
V_{CCINT}	Supply voltage relative to GND(2)		–0.5 to 3.0	V
V_{CCO}	Supply voltage relative to GND(2)		–0.5 to 4.0	V
V_{REF}	Input Reference Voltage		–0.5 to 3.6	V
V_{IN}	Input voltage relative to GND(3)	Using V_{REF}	–0.5 to 3.6	V
		Internal threshold	–0.5 to 5.5	V
V_{TS}	Voltage applied to 3-state output		–0.5 to 5.5	V
V_{CC}	Longest Supply Voltage Rise Time from 1V-2.375V		50	ms
T_{STG}	Storage temperature (ambient)		–65 to +150	°C
T_J	Junction temperature(4)	Plastic Packages	+125	°C

Notes:

1. Stresses beyond those listed under Absolute Maximum Ratings can cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time can affect device reliability.
2. Power supplies can turn on in any order.
3. For protracted periods (e.g., longer than a day), V_{IN} should not exceed V_{CCO} by more than 3.6 V.
4. For soldering guidelines and thermal considerations, see the "Device Packaging" information on www.xilinx.com.

Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CCINT}(1)	Input Supply voltage relative to GND, T_J = 0 °C to +85°C	Commercial	2.5 – 5%	2.5 + 5%	V
	Input Supply voltage relative to GND, T_J = –40°C to +100°C	Industrial	2.5 – 5%	2.5 + 5%	V
V_{CCO}(4)	Supply voltage relative to GND, T_J = 0 °C to +85°C	Commercial	1.4	3.6	V
	Supply voltage relative to GND, T_J = –40°C to +100°C	Industrial	1.4	3.6	V
T_{IN}	Input signal transition time			250	ns

Notes:

1. Correct operation is guaranteed with a minimum V_{CCINT} of 2.375 V (Nominal V_{CCINT} –5%). Below the minimum value, all delay parameters increase by 3% for each 50-mV reduction in V_{CCINT} below the specified range.
2. At junction temperatures above those listed as Operating Conditions, delay parameters do increase. Please refer to the TRCE report.
3. Input and output measurement threshold is ~50% of V_{CC}.
4. Min and Max values for V_{CCO} are I/O Standard dependant.

CLB Arithmetic Switching Characteristics

Setup times not listed explicitly can be approximated by decreasing the combinatorial delays by the setup time adjustment listed. Precise values are provided by the timing analyzer.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
F operand inputs to X via XOR	T_{OPX}	0.37	0.8	0.9	1.0	ns, max
F operand input to XB output	T_{OPXB}	0.54	1.1	1.3	1.4	ns, max
F operand input to Y via XOR	T_{OPY}	0.8	1.5	1.7	2.0	ns, max
F operand input to YB output	T_{OPYB}	0.8	1.5	1.7	2.0	ns, max
F operand input to COUT output	T_{OPCYF}	0.6	1.2	1.3	1.5	ns, max
G operand inputs to Y via XOR	T_{OPGY}	0.46	1.0	1.1	1.2	ns, max
G operand input to YB output	T_{OPGYB}	0.8	1.6	1.8	2.1	ns, max
G operand input to COUT output	T_{OPCYG}	0.7	1.3	1.4	1.6	ns, max
BX initialization input to COUT	T_{BXCY}	0.41	0.9	1.0	1.1	ns, max
CIN input to X output via XOR	T_{CINX}	0.21	0.41	0.46	0.53	ns, max
CIN input to XB	T_{CINXB}	0.02	0.04	0.05	0.06	ns, max
CIN input to Y via XOR	T_{CINY}	0.23	0.46	0.52	0.6	ns, max
CIN input to YB	T_{CINYB}	0.23	0.45	0.51	0.6	ns, max
CIN input to COUT output	T_{BYP}	0.05	0.09	0.10	0.11	ns, max
Multiplier Operation						
F1/2 operand inputs to XB output via AND	T_{FANDXB}	0.18	0.36	0.40	0.46	ns, max
F1/2 operand inputs to YB output via AND	T_{FANDYB}	0.40	0.8	0.9	1.1	ns, max
F1/2 operand inputs to COUT output via AND	T_{FANDCY}	0.22	0.43	0.48	0.6	ns, max
G1/2 operand inputs to YB output via AND	T_{GANDYB}	0.25	0.50	0.6	0.7	ns, max
G1/2 operand inputs to COUT output via AND	T_{GANDCY}	0.07	0.13	0.15	0.17	ns, max
Setup and Hold Times before/after Clock CLK(1)	Setup Time / Hold Time					
CIN input to FFX	T_{CCKX}/T_{CKCX}	0.50 / 0	1.0 / 0	1.2 / 0	1.3 / 0	ns, min
CIN input to FFY	T_{CCKY}/T_{CKCY}	0.53 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Block RAM Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Sequential Delays						
Clock CLK to DOUT output	T_{BCKO}	1.7	3.4	3.8	4.3	ns, max
Setup and Hold Times before/after Clock CLK(1)	Setup Time / Hold Time					
ADDR inputs	T_{BACK}/T_{BCKA}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
DIN inputs	T_{BDCK}/T_{BCKD}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
EN input	T_{BECK}/T_{BCKE}	1.3 / 0	2.6 / 0	3.0 / 0	3.4 / 0	ns, min
RST input	T_{BRCK}/T_{BCKR}	1.3 / 0	2.5 / 0	2.7 / 0	3.2 / 0	ns, min
WEN input	T_{BWCK}/T_{BCKW}	1.2 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T_{BPWH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T_{BPWL}	0.8	1.5	1.7	2.0	ns, min
CLKA -> CLKB setup time for different ports	T_{BCCS}		3.0	3.5	4.0	ns, min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

TBUF Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
IN input to OUT output	T_{IO}	0	0	0	0	ns, max
TRI input to OUT output high-impedance	T_{OFF}	0.05	0.09	0.10	0.11	ns, max
TRI input to valid data on OUT output	T_{ON}	0.05	0.09	0.10	0.11	ns, max

JTAG Test Access Port Switching Characteristics

Description	Symbol	Speed Grade			Units
		-6	-5	-4	
TMS and TDI Setup times before TCK	T_{TAPTCK}	4.0	4.0	4.0	ns, min
TMS and TDI Hold times after TCK	T_{TCKTAP}	2.0	2.0	2.0	ns, min
Output delay from clock TCK to output TDO	T_{TCKTDO}	11.0	11.0	11.0	ns, max
Maximum TCK clock frequency	F_{TCK}	33	33	33	MHz, max

Minimum Clock-to-Out for Virtex Devices

I/O Standard	With DLL	Without DLL									
	All Devices	V50	V100	V150	V200	V300	V400	V600	V800	V1000	Units
*LVTTL_S2	5.2	6.0	6.0	6.0	6.0	6.1	6.1	6.1	6.1	6.1	ns
*LVTTL_S4	3.5	4.3	4.3	4.3	4.3	4.4	4.4	4.4	4.4	4.4	ns
*LVTTL_S6	2.8	3.6	3.6	3.6	3.6	3.7	3.7	3.7	3.7	3.7	ns
*LVTTL_S8	2.2	3.1	3.1	3.1	3.1	3.1	3.1	3.2	3.2	3.2	ns
*LVTTL_S12	2.0	2.9	2.9	2.9	2.9	2.9	2.9	3.0	3.0	3.0	ns
*LVTTL_S16	1.9	2.8	2.8	2.8	2.8	2.8	2.8	2.9	2.9	2.9	ns
*LVTTL_S24	1.8	2.6	2.6	2.7	2.7	2.7	2.7	2.7	2.7	2.8	ns
*LVTTL_F2	2.9	3.8	3.8	3.8	3.8	3.8	3.8	3.9	3.9	3.9	ns
*LVTTL_F4	1.7	2.6	2.6	2.6	2.6	2.6	2.6	2.7	2.7	2.7	ns
*LVTTL_F6	1.2	2.0	2.0	2.0	2.1	2.1	2.1	2.1	2.1	2.2	ns
*LVTTL_F8	1.1	1.9	1.9	1.9	1.9	2.0	2.0	2.0	2.0	2.0	ns
*LVTTL_F12	1.0	1.8	1.8	1.8	1.8	1.9	1.9	1.9	1.9	1.9	ns
*LVTTL_F16	0.9	1.7	1.8	1.8	1.8	1.8	1.8	1.8	1.9	1.9	ns
*LVTTL_F24	0.9	1.7	1.7	1.7	1.8	1.8	1.8	1.8	1.8	1.9	ns
LVCMOS2	1.1	1.9	1.9	1.9	2.0	2.0	2.0	2.0	2.0	2.1	ns
PCI33_3	1.5	2.4	2.4	2.4	2.4	2.4	2.4	2.5	2.5	2.5	ns
PCI33_5	1.4	2.2	2.2	2.3	2.3	2.3	2.3	2.3	2.3	2.4	ns
PCI66_3	1.1	1.9	1.9	2.0	2.0	2.0	2.0	2.0	2.1	2.1	ns
GTL	1.6	2.5	2.5	2.5	2.5	2.5	2.5	2.6	2.6	2.6	ns
GTL+	1.7	2.5	2.5	2.6	2.6	2.6	2.6	2.6	2.6	2.7	ns
HSTL I	1.1	1.9	1.9	1.9	1.9	2.0	2.0	2.0	2.0	2.0	ns
HSTL III	0.9	1.7	1.7	1.8	1.8	1.8	1.8	1.8	1.8	1.9	ns
HSTL IV	0.8	1.6	1.6	1.6	1.7	1.7	1.7	1.7	1.7	1.8	ns
SSTL2 I	0.9	1.7	1.7	1.7	1.7	1.8	1.8	1.8	1.8	1.8	ns
SSTL2 II	0.8	1.6	1.6	1.6	1.6	1.7	1.7	1.7	1.7	1.7	ns
SSTL3 I	0.8	1.6	1.7	1.7	1.7	1.7	1.7	1.7	1.8	1.8	ns
SSTL3 II	0.7	1.5	1.5	1.6	1.6	1.6	1.6	1.6	1.6	1.7	ns
CTT	1.0	1.8	1.8	1.8	1.9	1.9	1.9	1.9	1.9	2.0	ns
AGP	1.0	1.8	1.8	1.9	1.9	1.9	1.9	1.9	1.9	2.0	ns

*S = Slow Slew Rate, F = Fast Slew Rate

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Input and output timing is measured at 1.4 V for LVTTL. For other I/O standards, see Table 3. In all cases, an 8 pF external capacitive load is used.

DLL Timing Parameters

All devices are 100 percent functionally tested. Because of the difficulty in directly measuring many internal timing parameters, those parameters are derived from benchmark timing patterns. The following guidelines reflect worst-case values across the recommended operating conditions.

Description	Symbol	Speed Grade						Units
		-6		-5		-4		
		Min	Max	Min	Max	Min	Max	
Input Clock Frequency (CLKDLLHF)	FCLKINHF	60	200	60	180	60	180	MHz
Input Clock Frequency (CLKDLL)	FCLKINLF	25	100	25	90	25	90	MHz
Input Clock Pulse Width (CLKDLLHF)	$T_{DLLPWHF}$	2.0	-	2.4	-	2.4	-	ns
Input Clock Pulse Width (CLKDLL)	$T_{DLLPWLF}$	2.5	-	3.0		3.0	-	ns

Notes:

1. All specifications correspond to Commercial Operating Temperatures (0°C to + 85°C).

DLL Clock Tolerance, Jitter, and Phase Information

All DLL output jitter and phase specifications determined through statistical measurement at the package pins using a clock mirror configuration and matched drivers.

Description	Symbol	F_{CLKIN}	CLKDLLHF		CLKDLL		Units
			Min	Max	Min	Max	
Input Clock Period Tolerance	T_{IPTOL}		-	1.0	-	1.0	ns
Input Clock Jitter Tolerance (Cycle to Cycle)	T_{IJITCC}		-	± 150	-	± 300	ps
Time Required for DLL to Acquire Lock	T_{LOCK}	> 60 MHz	-	20	-	20	µs
		50 - 60 MHz	-	-	-	25	µs
		40 - 50 MHz	-	-	-	50	µs
		30 - 40 MHz	-	-	-	90	µs
		25 - 30 MHz	-	-	-	120	µs
Output Jitter (cycle-to-cycle) for any DLL Clock Output(1)	T_{OJITCC}			± 60		± 60	ps
Phase Offset between CLKIN and CLKO(2)	T_{PHIO}			± 100		± 100	ps
Phase Offset between Clock Outputs on the DLL(3)	T_{PHOO}			± 140		± 140	ps
Maximum Phase Difference between CLKIN and CLKO(4)	T_{PHIOM}			± 160		± 160	ps
Maximum Phase Difference between Clock Outputs on the DLL(5)	T_{PHOOM}			± 200		± 200	ps

Notes:

1. **Output Jitter** is cycle-to-cycle jitter measured on the DLL output clock, *excluding* input clock jitter.
2. **Phase Offset between CLKIN and CLKO** is the worst-case fixed time difference between rising edges of CLKIN and CLKO, *excluding* Output Jitter and input clock jitter.
3. **Phase Offset between Clock Outputs on the DLL** is the worst-case fixed time difference between rising edges of any two DLL outputs, *excluding* Output Jitter and input clock jitter.
4. **Maximum Phase Difference between CLKIN an CLKO** is the sum of Output Jitter and Phase Offset between CLKIN and CLKO, or the greatest difference between CLKIN and CLKO rising edges due to DLL alone (*excluding* input clock jitter).
5. **Maximum Phase DIfference between Clock Outputs on the DLL** is the sum of Output JItter and Phase Offset between any DLL clock outputs, or the greatest difference between any two DLL output rising edges sue to DLL alone (*excluding* input clock jitter).
6. All specifications correspond to Commercial Operating Temperatures (0°C to +85°C).

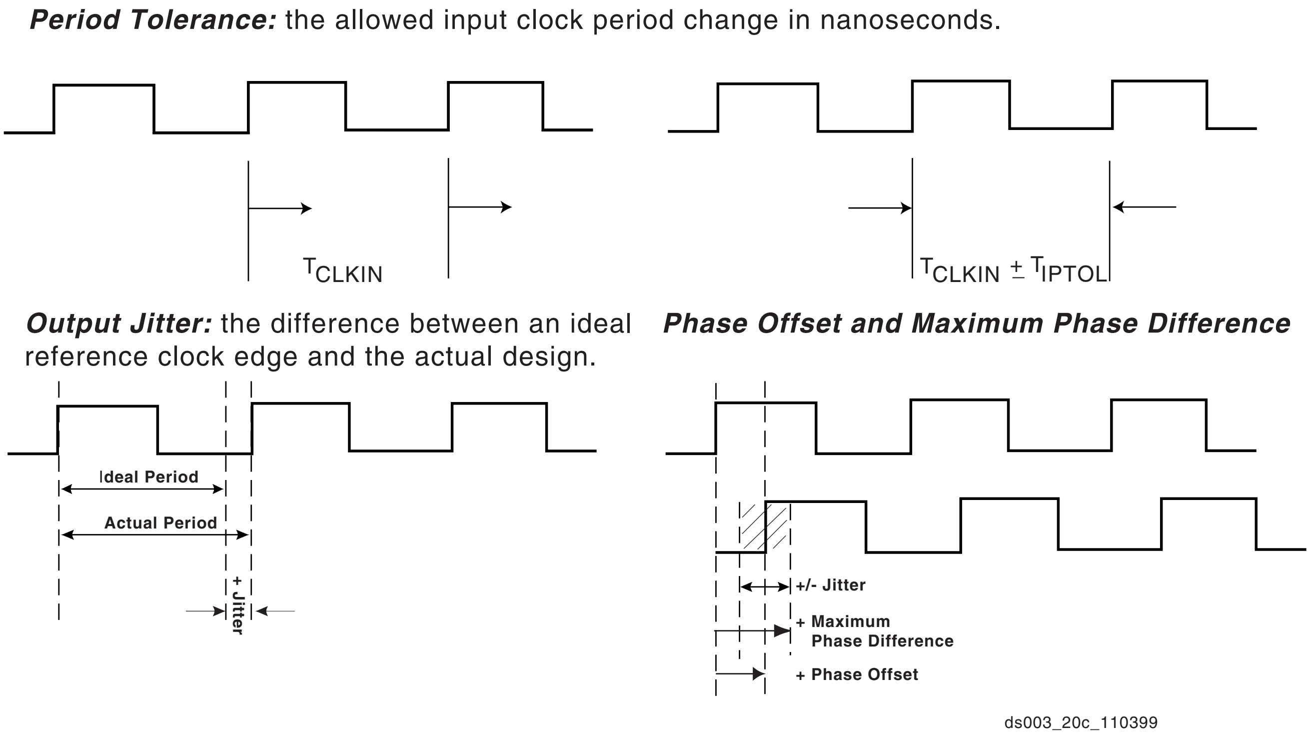

Figure 1: **Frequency Tolerance and Clock Jitter**

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Table 2: **Virtex Pinout Tables (Chip-Scale and QFP Packages)** ***(Continued)***

Pin Name	Device	CS144	TQ144	PQ/HQ240
V_{CCO}	All	Banks 0 and 1: A2, A13, D7 Banks 2 and 3: B12, G11, M13 Banks 4 and 5: N1, N7, N13 Banks 6 and 7: B2, G2, M2	No I/O Banks in this package: 1, 17, 37, 55, 73, 92, 109, 128	No I/O Banks in this package: 15, 30, 44, 61, 76, 90, 105, 121, 136, 150, 165, 180, 197, 212, 226, 240
V_{REF}, Bank 0 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	C4, D6	5, 13	218, 232
	XCV100/150	... + B4	... + 7	... + 229
	XCV200/300	N/A	N/A	... + 236
	XCV400	N/A	N/A	... + 215
	XCV600	N/A	N/A	... + 230
	XCV800	N/A	N/A	... + 222
V_{REF}, Bank 1 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	A10, B8	22, 30	191, 205
	XCV100/150	... + D9	... + 28	... + 194
	XCV200/300	N/A	N/A	... + 187
	XCV400	N/A	N/A	... + 208
	XCV600	N/A	N/A	... + 193
	XCV800	N/A	N/A	... + 201
V_{REF}, Bank 2 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	D11, F10	42, 50	157, 171
	XCV100/150	... + D13	... + 44	... + 168
	XCV200/300	N/A	N/A	... + 175
	XCV400	N/A	N/A	... + 154
	XCV600	N/A	N/A	... + 169
	XCV800	N/A	N/A	... + 161

Table 4: **Virtex Pinout Tables (Fine-Pitch BGA)**

Pin Name	Device	FG256	FG456	FG676	FG680
GCK0	All	N8	W12	AA14	AW19
GCK1	All	R8	Y11	AB13	AU22
GCK2	All	C9	A11	C13	D21
GCK3	All	B8	C11	E13	A20
M0	All	N3	AB2	AD4	AT37
M1	All	P2	U5	W7	AU38
M2	All	R3	Y4	AB6	AT35
CCLK	All	D15	B22	D24	E4
PROGRAM	All	P15	W20	AA22	AT5
DONE	All	R14	Y19	AB21	AU5
INIT	All	N15	V19	Y21	AU2
BUSY/DOUT	All	C15	C21	E23	E3
D0/DIN	All	D14	D20	F22	C2
D1	All	E16	H22	K24	P4
D2	All	F15	H20	K22	P3
D3	All	G16	K20	M22	R1
D4	All	J16	N22	R24	AD3
D5	All	M16	R21	U23	AG2
D6	All	N16	T22	V24	AH1
D7	All	N14	Y21	AB23	AR4
WRITE	All	C13	A20	C22	B4
CS	All	B13	C19	E21	D5
TDI	All	A15	B20	D22	B3
TDO	All	B14	A21	C23	C4
TMS	All	D3	D3	F5	E36
TCK	All	C4	C4	E6	C36
DXN	All	R4	Y5	AB7	AV37
DXP	All	P4	V6	Y8	AU35

Table 4: **Virtex Pinout Tables (Fine-Pitch BGA)** ***(Continued)***

Pin Name	Device	FG256	FG456	FG676	FG680
V_{CCINT}	All	C3, C14, D4, D13, E5, E12, M5, M12, N4, N13, P3, P14	E5, E18, F6, F17, G7, G8, G9, G14, G15, G16, H7, H16, J7, J16, P7, P16, R7, R16, T7, T8, T9, T14, T15, T16, U6, U17, V5, V18	G7, G20, H8, H19, J9, J10, J11, J16, J17, J18, K9, K18, L9, L18, T9, T18, U9, U18, V9, V10, V11, V16, V17, V18, W8, W19, Y7, Y20	AD5, AD35, AE5, AE35, AL5, AL35, AM5, AM35, AR8, AR9, AR15, AR16, AR24, AR25, AR31, AR32, E8, E9, E15, E16, E24, E25, E31, E32, H5, H35, J5, J35, R5, R35, T5, T35
V_{CCO}, Bank 0	All	E8, F8	F7, F8, F9, F10 G10, G11	H9, H10, H11, H12, J12, J13	E26, E27, E29, E30, E33, E34
V_{CCO}, Bank 1	All	E9, F9	F13, F14, F15, F16, G12, G13	H15, H16, H17, H18, J14, J15	E6, E7, E10, E11, E13, E14
V_{CCO}, Bank 2	All	H11, H12	G17, H17, J17, K16, K17, L16	J19, K19, L19, M18, M19, N18	F5, G5, K5, L5, N5, P5
V_{CCO}, Bank 3	All	J11, J12	M16, N16, N17, P17, R17, T17	P18, R18, R19, T19, U19, V19	AF5, AG5, AN5, AK5, AJ5, AP5
V_{CCO}, Bank 4	All	L9. M9	T12, T13, U13, U14, U15, U16,	V14, V15, W15, W16, W17, W18	AR6, AR7, AR10, AR11, AR13, AR14
V_{CCO}, Bank 5	All	L8, M8	T10, T11, U7, U8, U9, U10	V12, V13, W9,W10, W11, W12	AR26, AR27, AR29, AR30, AR33, AR34
V_{CCO}, Bank 6	All	J5, J6	M7, N6, N7, P6, R6, T6	P9, R8, R9, T8, U8, V8	AF35, AG35, AJ35, AK35, AN35, AP35
V_{CCO}, Bank 7	All	H5, H6	G6, H6, J6, K6, K7, L7	J8, K8, L8, M8, M9, N9	F35, G35, K35, L35, N35, P35
V_{REF}, Bank 0 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	B4, B7	N/A	N/A	N/A
	XCV100/150	... + C6	A9, C6, E8	N/A	N/A
	XCV200/300	... + A3	... + B4	N/A	N/A
	XCV400	N/A	N/A	A12, C11, D6, E8, G10	
	XCV600	N/A	N/A	... + B7	A33, B28, B30, C23, C24, D33
	XCV800	N/A	N/A	... + B10	... + A26
	XCV1000	N/A	N/A	N/A	... + D34

Table 4: **Virtex Pinout Tables (Fine-Pitch BGA)** ***(Continued)***

Pin Name	Device	FG256	FG456	FG676	FG680
No Connect (No-connect pins are listed incrementally. All pins listed for both the required device and all larger devices listed in the same package are no connects.)	XCV800	N/A	N/A	A2, A3, A15, A25, B1, B6, B11, B16, B21, B24, B26, C1, C2, C25, C26, F2, F6, F21, F25, L2, L25, N25, P2, T2, T25, AA2, AA6, AA21, AA25, AD1, AD2, AD25, AE1, AE3, AE6, AE11, AE14, AE16, AE21, AE24, AE26, AF2, AF24, AF25	N/A
	XCV600	N/A	N/A	same as above	N/A
	XCV400	N/A	N/A	... + A9, A10, A13, A16, A24, AC1, AC25, AE12, AE15, AF3, AF10, AF11, AF13, AF14, AF16, AF18, AF23, B4, B12, B13, B15, B17, D1, D25, H26, J1, K26, L1, M1, M25, N1, N26, P1, P26, R2, R26, T1, T26, U26, V1	N/A
	XCV300	N/A	D4, D19, W4, W19	N/A	N/A
	XCV200	N/A	... + A2, A6, A12, B11, B16, C2, D1, D18, E17, E19, G2, G22, L2, L19, M2, M21, R3, R20, U3, U18, Y22, AA1, AA3, AA11, AA16, AB7, AB12, AB21,	N/A	N/A
	XCV150	N/A	... + A13, A14, C8, C9, E13, F11, H21, J1, J4, K2, K18, K19, M17, N1, P1, P5, P22, R22, W13, W15, AA9, AA10, AB8, AB14	N/A	N/A